FOREWORD

Special Section on Machine Vision and its Applications

The Eleventh IAPR Conference on Machine Vision Applications, MVA2009, was held in Keio University from May 20 through 22, 2009. Reflecting growing areas of machine vision applications, which include surveillance, measurement, control, interaction, and various object recognition, the conference attracted about 150 submissions from 29 countries in spite of serious recession and swine flu. We selected 39 oral and 83 poster presentations, and the conference was quite active in friendly atmosphere. Encouraged by the great success of the conference, we planned this special section and asked the conference participants and other researchers in this field to submit papers. We received 48 papers, and we have selected 14 papers among them through rigorous review process. We believe that the papers show the high quality of current machine vision research and wide variety of applications. We would like to express our sincere gratitude to all the authors for their valuable contributions and to all the reviewers for their cooperation in completing the reviewing process under a tight schedule.

Special Section Editorial Committee

Guest Associate Editor:

Hideo Saito (Keio University)

Guest Editorial Manager:

Hiroaki Nakai (Toshiba Medical Systems)

Members:

Yoshimitsu Aoki (Keio University), Kenichi Arakawa (NTT), Masakazu Ejiri (Research Consultant), Osamu Hori (Toshiba), Ichiro Ide (Nagoya University), Katsushi Ikeuchi (The University of Tokyo), Hiroshi Ishikawa (Nagoya City University), Tatsuhiko Kagehiro (Hitachi), Masataka Kagesawa (The University of Tokyo), Yasuyo Kita (AIST), Hiroyasu Koshimizu (Chukyo University), Yoshinori Kuno (Saitama University), Atsuto Maki (Toshiba Research Europe), Takeshi Masuda (AIST), Hiroshi Nagagashi (Tokyo Institute of Technology), Akio Nakamura (Tokyo Denki University), Keisuke Nakashima (Hitachi), Kunio Nobori (Panasonic), Akio Okazaki (Tsukuba University of Technology), Shin'ichiro Okazaki (NEC), Kazunori Onoguchi (Hirosaki University), Katsuhiko Sakaue (AIST), Hiroshi Sako (Hitachi), Shigeru Sasaki (Fujitsu), Yoichi Sato (The University of Tokyo), Eigo Segawa (Fujitsu), Shuji Senda (NEC), Takeshi Shakunaga (Okayama University), Hisae Shibuya (Hitachi), Ikuko Shimizu (Tokyo University of Agriculture and Technology), Kyoko Sudo (NTT IT), Kazuhiko Sumi (Mitsubishi Electric), Johji Tajima (Nagoya City University), Norimichi Ukita (NAIST), Koji Wakimoto (Mitsubishi Electric), Mutsumi Watanabe (Kagoshima University)

Ken-ichi Maeda, Guest Editor-in-Chief

Ken-ichi Maeda (*Fellow*) received the B.S. degree in physical electronics, the M.S. degree in electrical engineering, and the Ph.D. degree in information processing from Tokyo Institute of Technology in 1974, 1976, and 2007, respectively. He joined Toshiba Corporation in 1976. He was a visiting scholar at Artificial Intelligence Applications Institute of the University of Edinburgh from 1989 to 1990, Head of Kansai Research Center of Toshiba Corporation from 1999 to 2000, and Senior Fellow at Corporate Research and Development Center, Toshiba Corporation from 2004 to 2009. He is currently Senior Fellow at Toshiba Research Consulting Corporation. His research interests include pattern recognition, computer vision, and computer architecture. Dr. Maeda is Senior Member of IEEE.